


<b>Search Notes</b>  	<b>Application/Control No.</b>  10540658	<b>Applicant(s)/Patent Under Reexamination</b>  MATHIES ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
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SEARCH NOTES		
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/8/2008	/YJK/
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INTERFERENCE SEARCH			
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